

Amendments to the Specification

Please replace the paragraph at Page 2, line 16 - Page 2, line 7 of the Specification, with the following paragraph:

Specifically, the rounded groove 21 produces a curved, exposed peripheral junction surface [[is]], preventing contamination by rubbing contacts with dust particles. Such contacts form, e.g., metallic shorting paths and drastically reduce the device yield by increasing leakage current and decreasing breakdown voltage. Li's 3,430,109 patent discloses at column 5, lines 15-20 that for a one-micron (thick) PN junction region, a single-atomic gold chain on-micron long contains 3,903 gold atoms giving a leakage current of 0.15 ma at 50 volts thereby destroying the device. A single 1-micron gold particle could possibly destroy 7.977×10^6 particles.